

### PCN# 20140115002 Qualification of Cu as Alternative Wire Base Metal for Selected Device(s) Change Notification / Sample Request

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN ww admin team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

## PCN# 20140115002 Attachment: 1

# **Products Affected:**

According to our records, there are the affected device(s) that you have purchased within the past twenty-four (24) months. Technical details of this Product Change follow on the next page(s).

PCN	Number:	20140	)115002					PCN Date: 01/22/2014		
Title: Qualification of Cu as Alternative Wire Base Metal for Selected Device(s)										
Customer Contact:PCN ManagerPhone:+1(214)480-6037Dept:Quality Ser					uality Services					
Prop	oosed 1 <sup>st</sup> Ship			ate provided at Imple request						
Chai	nge Type:									
$\boxtimes$	Assembly Site		Assemb	ly Proce	ess		$\boxtimes$	Assembly N	4ate	erials
	Design		Electrica	al Speci	fica	tion		Mechanical	Sp	ecification
$\boxtimes$	Test Site		Packing	/Shippiı	ng/l	Labeling		Test Proces	SS	
	Wafer Bump S	Site	Wafer B	Sump Ma	ater	rial		Wafer Bum	p P	rocess
	Wafer Fab Sit	e [	Wafer F	Wafer Fab Materials				Wafer Fab Process		cess
			Part nui	mber ch	ang	je				
				PCI	NC	Details				

#### **Description of Change:**

Texas Instruments is pleased to announce the qualification of Cu as an additional bond wire option for devices listed in "Product affected" section below. Material differences are shown in the following table:

## **Group 1 Device: Devices will remain in current assembly facility**

	From	То
Wire type	Au	Cu
Mold Compound	R-13	R-17
Leadframe Finish	NiPdAu	Matte Sn

Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part number</u>, for example; <u>SN001066DBVR</u> – can ship with both Matte Sn and NiPdAu.

## Group 2 Device: MLA as additional Assembly and Test Site

	CAR	MLA
Wire type	Au	Cu
Mold Compound	438578	4206193

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

#### **Reason for Change:**

Continuity of supply.

- 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties
- 2) Maximize flexibility within our Assembly/Test production sites.
- 3) Cu is easier to obtain and stock

Anticipated im	pact on Fit, Form, Function,	<b>Quality or Relial</b>	bility (positive / negative):			
None.						
Changes to pro	oduct identification resulting	from this PCN:				
Group 1 Device	e: Devices will remain in cur	rent assembly fa		<b></b> ]		
			ECAT: G4 = NiPdAu ECAT: G3 = Matte Sn			
Assembly Site						
NFME	Assembly Site Origin (22L)	ASO:NFME	ECAT:G4			
NFME	Assembly Site Origin (22L)	ASO: NFME	ECAT:G3			
TEXAS INSTRUMENTS MADE IN: Malaysi 2DC: 2/260C/1 YE MSL 2 /260C/1 YE MSL 1 /235C/UNLIN OPT: ITEM: LBL: 5A (L) Group 2 Device Assembly Site	AR SEAL DT M 03/29/04 39 T0:1750	1P) SN74LS07NSR (Q) 2000 (D) 31T)LOT: 395904 4W) TKY(1T) 7523 (P) REV: (V) ( 0L) CS0: SHE (21L) (2L) AS0: MLA (23L)	0336 7MLA 483SI2 0033317 cco:USA ACO: MYS			
CARSEM Malays	·	te Origin (22L)	ASO: CAR			
TI Malaysia ASSEMBLY SITE		te Origin (22L)	ASO: MLA			
ASSEMBLY SITE CODES: CAR = V, MLA = K Sample product shipping label (not actual product label)						

Product Affected: Group 1 Device					
SN001066DBVR	SN74AHCT1G04DBVT	SN74AUP1G17DBVT	SN74LVC1G332DBVR		
SN003166DBVR	SN74AHCT1G08DBVR	SN74AUP1G97DBVR	SN74LVC1G79DBVR		
SN74AHC1G02DBVR	SN74AHCT1G08DBVT	SN74CB3T1G125DBVR	SN74LVC1G79DBVT		
SN74AHC1G02DBVT	SN74AHCT1G125DBVR	SN74LVC1G00DBVR	SN74LVC1G80DBVR		
SN74AHC1G04DBVR	SN74AHCT1G125DBVT	SN74LVC1G00DBVT	SN74LVC1G80DBVT		
SN74AHC1G04DBVT	SN74AHCT1G126DBVR	SN74LVC1G02DBVR	SN74LVC1G86DBVR		
SN74AHC1G08DBVR	SN74AHCT1G126DBVT	SN74LVC1G02DBVT	SN74LVC1G86DBVT		
SN74AHC1G08DBVT	SN74AHCT1G32DBVR	SN74LVC1G06DBVR	SN74LVC1GU04DBVR		
SN74AHC1G09DBVR	SN74AHCT1G32DBVT	SN74LVC1G06DBVT	SN74LVC1GU04DBVT		
SN74AHC1G125DBVR	SN74AHCT1G86DBVR	SN74LVC1G07DBVR	SN74LVC2G04DBVR		
SN74AHC1G125DBVT	SN74AHCT1G86DBVT	SN74LVC1G07DBVT	SN74LVC2G04DBVT		
SN74AHC1G126DBVR	SN74AUC1G00DBVR	SN74LVC1G11DBVR	SN74LVC2G07DBVR		
SN74AHC1G126DBVT	SN74AUC1G07DBVR	SN74LVC1G126DBVR	SN74LVC2G14DBVR		
SN74AHC1G32DBVR	SN74AUC1G07DBVT	SN74LVC1G126DBVT	SN74LVC2G14DBVT		
SN74AHC1G32DBVT	SN74AUC1G14DBVR	SN74LVC1G14DBVR	SN74LVC2G17DBVR		
SN74AHC1G86DBVR	SN74AUC1G17DBVR	SN74LVC1G14DBVT	SN74LVC2G17DBVT		
SN74AHC1G86DBVT	SN74AUC1G32DBVR	SN74LVC1G17DBVR	SN74LVC2G34DBVR		
SN74AHC1GU04DBVR	SN74AUC1G66DBVR	SN74LVC1G17DBVT	SN74LVC2G34DBVT		
SN74AHC1GU04DBVT	SN74AUC2G07DBVR	SN74LVC1G240DBVR	TS5A1066DBVR		
SN74AHCT1G00DBVR	SN74AUP1G04DBVR	SN74LVC1G240DBVT	TS5A3166DBVR		
SN74AHCT1G00DBVT	SN74AUP1G04DBVT	SN74LVC1G27DBVR	TS5A3167DBVR		
SN74AHCT1G02DBVR	SN74AUP1G07DBVR	SN74LVC1G3157DBVR	TS5A63157DBVR		
SN74AHCT1G02DBVT	SN74AUP1G08DBVR	SN74LVC1G32DBVR			
SN74AHCT1G04DBVR	SN74AUP1G17DBVR	SN74LVC1G32DBVT			
Product Affected: Grou	p 2 Device				
UCC3895PW	UCC3895PWG4	UCC3895PWTR	JCC3895PWTRG4		

Qualification Data : Group 1					
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.					
Qua	Qual Vehicle 1 : TL432ACDBVR (MSL 1-260C)				
	Package Cor	struction Details			
Assembly Site:	NFME	Mold Compound:	R-17		
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound:	A-03		
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia., Cu		

Qualification: 🗌 Plan 🛛	Test Results					
Poliphility Test	Conditions		San	nple Size/	'Fail	
Reliability Test	Conditions	Conditions		Lot# 2	Lot# 3	
Electrical Characterization	-		Pass	-	-	
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (5	-65C/+150C (500 Cyc)			77/0	
**High Temp. Storage Bake	170C (600 hrs)	170C (600 hrs)			77/0	
**Autoclave	121C (192 hrs)		77/0 77/0	77/0	77/0	
**Biased HAST	130C/85%RH (	192 hrs)	77/0	77/0	77/0	
**Life Test	150C (300 hrs)		77/0	77/0	77/0	
Solderability		ours; PB-Free solder	22/0	22/0	22/0	
X-ray	(top side only)	,	5/0	5/0	5/0	
Flammability	(IEC 695-2-2)		5/0	5/0	-	
Flammability	(UL-1694)		5/0	5/0	-	
Flammability	UL 94V-0)		5/0	5/0	-	
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass	
Moisture Sensitivity	(level 1 @ 2600		12/0	12/0	12/0	
Notes **- Preconditioning se	quence: Level 1-2	260C.	,			
		211DBVR (MSL 1-260C)				
		struction Details				
Assembly Site:	NFME	Mold Compound:	R-17			
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound:	: A-03			
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia., Cu			
Qualification: Plan	Test Results					
			Sample Size/Fail			
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3	
Electrical Characterization	-		Pass	-	-	
**Unbiased HAST	130C/85%RH/3	3.3 psia (192 hrs)	77/0	77/0	77/0	
**T/C -65C/150C		-65C/+150C (500 Cyc)		77/0	77/0	
**High Temp. Storage Bake	170C (600 hrs)		77/0	77/0	77/0	
**Autoclave	121C (192 hrs)		77/0	77/0	77/0	
**Life Test	150C (300 hrs)		77/0	-	-	
Solderability	Steam age, 8 h	ours; PB-Free solder	22/0	-	-	
X-ray			5/0	5/0	5/0	
Flammability	(IEC 695-2-2)			-	-	
Flammability	(UL-1694)		5/0 5/0	-	-	
Flammability	UL 94V-0)		5/0	-	-	
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass	
Moisture Sensitivity	(level 1 @ 2600		12/0	12/0	12/0	
Notes **- Preconditioning se						

Qual Vehicle 3 : INA193AIDBVR (MSL 2-260C)							
Package Construction Details							
Assembly Site:	NFME	Mold Compound:	R-17				
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound:	A-03				
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia.,	Cu			
Qualification: 🗌 Plan	Test Results		•				
Deliability Test	Conditions		Sample S	Size/Fail			
Reliability Test	Conditions		Lot# 1	Lot# 2			
Electrical Characterization	-		10/0	-			
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0			
**Biased HAST	130C/85%RH (	192 hrs)	77/0	77/0			
**T/C -65C/150C	-65C/+150C (5	00 Cyc)	77/0	77/0			
**High Temp. Storage Bake	150C (500 hrs)		77/0	77/0			
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass			
Moisture Sensitivity			12/0	12/0			
Notes **- Preconditioning s							
Qua		21AIDBVR (MSL 2-260C	)				
	Package Cor	struction Details					
Assembly Site:	NFME	Mold Compound:	R-17				
# Pins-Designator, Family:	6-DBV, SOT-23	Mount Compound:	A-03				
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia.,	Cu			
Qualification: 🗌 Plan	Test Results						
Reliability Test	Conditions		Sample S	ple Size/Fail			
Reliability Test	Conditions		Lot# 1	Lot# 2			
Electrical Characterization	-		10/0	-			
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0			
**Biased HAST	130C/85%RH (	192 hrs)	77/0	77/0			
**T/C -65C/150C	-65C/+150C (5	00 Cyc)	77/0	77/0			
**High Temp. Storage Bake	150C (500 hrs)	150C (500 hrs)		77/0			
X-ray	(top side only)		5/0	5/0			
Manufacturability (Assembly)	(per mfg. Site s	specification)	Pass	Pass			
Moisture Sensitivity	(level 2 @ 2600		12/0	12/0			
Notes **- Preconditioning s	equence: Level 2-2	260C.					

Qual Vehicle 5 : TPD4E001DBVR (MSL 1-260C)						
	Package Cor	nstruction Details				
Assembly Site:	NFME	Mold Compound:	R-17			
# Pins-Designator, Family:	6-DBV, SOT-23	Mount Compound:	A-03	A-03		
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil	1.0 Mil Dia., Cu		
Qualification: 🗌 Plan	Test Results	•				
Poliphility Test	Conditions	Conditions		Sample Size/Fail		
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3	
**Unbiased HAST	130C/85%RH/3	33.3 psia (192 hrs)	77/0	77/0	77/0	
**Biased HAST	130C/85%RH (	192 hrs)	77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (1	000 Cyc)	77/0	77/0	77/0	
**High Temp. Storage Bake	150C (1000 hrs	5)	77/0	77/0	-	
X-ray	(top side only)		5/0	5/0	5/0	
Manufacturability (Assembly)	(per mfg. Site s	(per mfg. Site specification)		Pass	Pass	
Moisture Sensitivity	(level 1 @ 2600	C peak +5/-0C)	12/0	12/0	12/0	
Notes **- Preconditioning s	equence: Level 1-2	260C.				

Qualification Data : Group 2 This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle 1 : BQ29330DBT (MSL 2-260C)						
Package Construction Details						
Assembly Site:	MLA	Mold Compound:	420619	93		
# Pins-Designator, Family:	30-DBT, TSSOP	Mount Compound:	4042500			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	0.96 Mil Dia., Cu		
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions		Sample Size/Fail			
Reliability Test			Lot# 1	Lot# 2	Lot# 3	
Electrical Characterization	-	Pass -		-		
**T/C -65C/150C	-65C/+150C (5	00 Сус)	77/0	77/0	77/0	
** Thermal Shock -65/150C	-65C/+150C (5	00 Сус)	77/0	77/0	77/0	
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0	
**Autoclave	121C (96 hrs) 77/0 77		77/0	77/0		
Manufacturability (Assembly)	embly) (per mfg. Site specification) Pass Pass			Pass		
Notes **- Preconditioning se	equence: Level 2-2	260C.				

Qual Vehicle 2 : ADS1230IPW (MSL 2-260C)						
Package Construction Details						
Assembly Site:	MLA	Mold Compound:	4206193			
# Pins-Designator, Family:	16-PW, TSSOP	Mount Compound:	404250	4042500		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cι	J	
Qualification: 🗌 Plan 🛛	Test Results					
Reliability Test	Conditions		Sample Size/Fail			
Reliability rest			Lot# 1	Lot# 2	Lot# 3	
**T/C -65C/150C	-65C/+150C (5	00 Cyc)	77/0	77/0	77/0	
** Thermal Shock -65/150C	-65C/+150C (5	00 Cyc)	77/0	77/0	77/0	
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0	
**Autoclave	121C (384 hrs)		77/0	77/0	77/0	
Manufacturability (Assembly)	(per mfg. Site specification)		Pass	Pass	Pass	
Moisture Sensitivity	(level 2 @ 2600	(level 2 @ 260C peak +5/-0C) 12		12/0	12/0	
Notes **- Preconditioning se	equence: Level 2-2	60C.				

Qual Vehicle 3 : CDCVF2505PW (MSL 1-260C)							
Package Construction Details							
Assembly Site: MLA Mold Compound: 4206193			93				
# Pins-Designator, Family:	8-PW, TSSOP	Mount Compound:	404250	00			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cu	l		
Qualification: 🗌 Plan	🛛 Test Results						
Poliphility Test	Conditions		San	nple Size/	'Fail		
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3		
**T/C -65C/150C	-65C/+150C (5	00 Сус)	77/0	77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (5	00 Cyc)	77/0	77/0	77/0		
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0		
**Autoclave	121C (96 hrs)		77/0	77/0	77/0		
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass		
Moisture Sensitivity	(level 1 @ 2600		12/0	12/0	12/0		
Notes **- Preconditioning s	equence: Level 1-2	60C.					
Qual V		VDS84ADGG (MSL 2-26	0C)				
	Package Cor	struction Details					
Assembly Site:	MLA	Mold Compound:	420619	93			
# Pins-Designator, Family:	48-DGG, TSSOP	Mount Compound:	404250	00			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cu	L		
Qualification: 🗌 Plan	🛛 Test Results						
Reliability Test	Conditions		San	nple Size/	'Fail		
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3		
**Unbiased HAST	130C/85%RH (	192 hrs)	77/0	77/0	77/0		
**T/C -65C/150C	-65C/+150C (5	-65C/+150C (500 Cyc)		77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (5	-65C/+150C (500 Cyc)		77/0	77/0		
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass		
Moisture Sensitivity	(level 2 @ 2600	C peak +5/-0C)	12/0	12/0	12/0		
Notes **- Preconditioning s	equence: Level 2-2	60C.					

Qual Vehicle 5 : THS7303PW (MSL 2-260C)						
Package Construction Details						
Assembly Site:	MLA	Mold Compound:	420619	4206193		
# Pins-Designator, Family:	20-PW, TSSOP	Mount Compound:	404250	4042500		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	0.96 Mil Dia., Cu		
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions		Sample Size/Fail			
			Lot# 1	Lot# 2	Lot# 3	
**High Temp. Storage Bake	170C (1000 hrs)		77/0	77/0	77/0	
**Autoclave	121C (384 hrs)		77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0	
** Thermal Shock -65/150C -65C/+150C (50		00 Cyc)	77/0	77/0	77/0	
Manufacturability (Assembly)	acturability (Assembly) (per mfg. Site specification)		Pass	Pass	Pass	
Moisture Sensitivity	(level 2 @ 260C peak +5/-0C)		12/0	12/0	12/0	
Notes **- Preconditioning sequence: Level 2-260C.						

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail	
USA	PCNAmericasContact@list.ti.com	
Europe	PCNEuropeContact@list.ti.com	
Asia Pacific	PCNAsiaContact@list.ti.com	
Japan	PCNJapanContact@list.ti.com	